

Notice of References Cited	Application/Control No. 10/604,796	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Hashem Farrokh	Art Unit 2187	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,240,504	05-2001	Boutaud et al.	712/38
*	B	US-6,343,353	01-2002	Kim, Hyun Eun	711/167
*	C	US-5,329,621	07-1994	Burgess et al.	710/107
*	D	US-5,465,343	11-1995	Henson et al.	711/112
*	E	US-2003/0233527	12-2003	Kawasaki et al.	712/1
*	F	US-5,668,971	09-1997	Neufeld, E. David	711/111
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.